

Overview of silicon sensor technology

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Overview

- □ Introduction to EIC vertex and tracking detector
- Technology selection
- □ MAPS in 65 nm technology / ITS3-derived EIC sensor
- EIC Silicon Consortium
- Conclusion



Introduction

- All EIC detector concepts proposed so far are equipped with a vertex and tracking detector as their innermost element
- This detector is needed to enable high precision measurements that are key to the EIC science programme
 - Determine primary vertices with high precision
 - Allow the measurement of secondary vertices for heavy-flavor decays
 - **Low**- p_{T} tracking
- This requires a well integrated, large acceptance vertex and tracking detector designed with high granularity and low material budget



Detector requirements

momentum resolution dp/p

Relative

Detector requirements matrix



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detector: pre-CDo baseline

sed detector concepts assumed as baseline nd tracking detector

> It has a barrel region composed of two to **outer tracking layers** with **0.3% X/X**₀, afiguration

ALICE Inner Tracking System Upgrade at LHC (ITS2)

Inner layer thickness = $0.3\% X/X_0$ Outer layer thickness = $0.8\% X/X_0$



J. Phys. G: Nucl. Part. Phys. 41 (2014) 087002

Image courtesy of Alexander Kiselev (BNL)

BNL: BeAST

Vertex and tracking detector: pre-CDo baseline

- Differently from ITS2, an EIC vertex and tracking detector also requires disks in the forward/backward region to provide full acceptance coverage
 - For example, BeAST has seven disks in each of these two regions
- Also, with respect to the ALPIDE sensor used in ITS2 a smaller pixel pitch and shorter integration time are needed
 - 20 µm pixel pitch is assumed as baseline
 - − Interaction frequency = $50 500 \text{ kHz} \rightarrow$ integration time down to 2 µs

ALPIDE sensor

180 nm Tower Jazz
28 x 28 μm² pixel pitch
~ 5 μs integration time
Power density 40 mW cm⁻²
50 kHz interaction rate (Pb-Pb)
200 kHz interaction rate (pp)



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Sensor technology choice

- A survey of silicon technologies has been presented at the <u>Temple EIC</u> <u>Yellow Report workshop</u>
- The sensor technology identified to satisfy the requirements of an EIC vertex and tracking detector is Monolithic Active Pixel Sensors
 - MAPS contain sensor and electronics in the same silicon substrate
- State-of-the-art MAPS detectors
 - MIMOSA sensor at STAR HFT
 - ALPIDE sensor at ALICE ITS
- □ More recent development
 - Depleted MAPS (i.e. HV/HR-CMOS)
 - 65 nm MAPS

Is there any existing or planned sensor that satisfies the EIC requirements?



Disclaimer

- Existing and planned MAPS sensors are shown for comparison purposes
 - This list is not exhaustive but represents the most applicable known designs based on work carried out by the authors
 - It is also not a review of development of MAPS sensors
- All considered MAPS sensors are fabricated in Tower Jazz (TJ) technology
 - This technology (differently from other such as LFoundry or AMS/TSI) allows for the design of a small collection electrode resulting in a small detector capacitance
 - This translates into low power (key for low material budget), compact FE design (key for small pixels), low noise



ALPIDE

- □ ALPIDE can meet the requirements with some work
 - Smaller pixel size: 28 to 20 μm
 - Shorten integration time: 5 to 2 μs
 - Possibly smaller power consumption to improve on the material budget requirements
- However the performance is marginal compared to the EIC requirements
- It is suggested that ALPIDE serves as a possible alternate backup sensor if existing efforts at new sensor designs are not successful or are delayed past the needed construction timeframe

https://indico.cern.ch/event/632608/attach ments/1445423/2239598/Detector_seminar _priedler_28042017_final.pdf



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MALTA

PWELL



Total power [mW/cm²]

NIEL [1MeV n_{eg}/cm²]

(matrix only)

~70 – 150 depending on rate

 $> 1.0 \times 10^{15}$

100

36.9/20.2

 1.7×10^{13}

2.7

TID [Mrad] L. Gonella | Overview of silicon sensor technology |

MALTA

- Significant modification/re-design needed to meet EIC requirements
- The current version of the sensor is a prototype, not experiment ready, more submissions planned to get to the final version of the sensor
- □ However...
 - An experiment ready version of the MALTA may be interesting for forward tracking with added timing, see LANL proposal for disks at large z
 - The TJ 180 nm modified technology itself could be used to design a dedicated EIC MAPS; a feasibility study had been carried out by RAL CMOS Sensor Design group and Birmingham, see <u>lain's talk</u>



New emerging development: 65 nm MAPS

- Recently, an effort is emerging to develop new generation MAPS in a
 65 nm CMOS imaging technology
- Large interest in the HEP community to develop this process for future experiments
 - ALICE ITS3 project
 - CERN Experimental Physics department R&D programme (WP1.2 MAPS)
- □ This path is more attractive for the development of an EIC MAPS
 - Improved performance for precision measurements at the EIC
 - Process availability on the EIC project timescale
 - ... but higher cost and complexity than older technology nodes



ITS₃/EIC projects overlap

- □ The ALICE ITS3 project aims at developing a new generation MAPS sensor at the 65 nm node with extremely low mass for the HL-LHC
 - See Giacomo's talk
- As presented by <u>Leo Greiner (LBNL) at the EIC Yellow Report Kick-Off</u> meeting, this effort is particularly interesting for the EIC
 - The ITS3 sensor specifications and development timescale are largely compatible with those of the EIC
 - Non-ALICE members are welcome to contribute to the R&D to develop and use the technology for other applications
- Joining the ITS3 collaboration, the EIC can leverage on a large effort at CERN, sharing development costs, to design an innovative sensor solution at the 65 nm node, suited for an experiment starting in ~ 2030

This has been identified has the most efficient way forward

ITS3 sensor vs. EIC sensor

 Detector
 Vertex and Tracking
 Time stamping layer

 Technology
 180 nm TJ CIS modified, 65 nm TJ

 Substrate Resistivity [kohm cm]
 1 or higher

 Collection Electrode
 Small

- □ The ITS3 sensor specifications even exceeded to the EIC requirements
 - Chosen technology: TJ 65 nm procesite the time tas p: TJ 180 20 x 20 max 350 x 350
 - Higher granularity and lower power computing with respect to current simulation baseline (ITS2/ALPIDE Bilk (H2)mm²] TBD Asynchronous
 - Shorter integration time, lower fake^{Power[mw/me2]} (and better time resolution) than required at the EIC TID [Mrad] <10 Noise [electrons] =10 + 14 + 50

Specifications

| Parameter | ALPIDE (existing) | Wafer-scale sensor (this proposal) |
|---------------------------|--|---------------------------------------|
| Technology node | 180 nm | 65 nm |
| Silicon thickness | 50 μm | 20-40 μm |
| Pixel size | 27 x 29 μm | O(10 x 10 μm) |
| Chip dimensions | 1.5 x 3.0 cm | scalable up to 28 x 10 cm |
| Front-end pulse duration | $\sim 5 \ \mu s$ | ~ 200 ns |
| Time resolution | $\sim 1 \ \mu s$ | < 100 ns (option: <10ns) |
| Max particle fluence | 100 MHz/cm^2 | 100 MHz/cm ² |
| Max particle readout rate | 10 MHz/cm ² | 100 MHz/cm ² |
| Power Consumption | 40 mW/cm^2 | $< 20 \text{ mW/cm}^2$ (pixel matrix) |
| Detection efficiency | > 99% | > 99% |
| Fake hit rate | $< 10^{-7}$ event/pixel | < 10 ⁻⁷ event/pixel |
| NIEL radiation tolerance | $\sim 3 \times 10^{13} 1 \text{ MeV} n_{eq}/\text{cm}^2$ | $10^{14} 1 \text{ MeV } n_{eq}/cm^2$ |
| TID radiation tolerance | 3 MRad | 10 MRad |

| Parameter | EIC Vertex and Tracking MAPS |
|--------------------------------------|---------------------------------|
| | TJ ISC 65 nm |
| Technology | (Backup: TJ CIS 180 nm) |
| Substrate Resistivity [kohm cm] | 1 or higher |
| Collection Electrode | Small |
| Detector Capacitance [fF] | <5 |
| Chip size [cm x cm] | Full reticule or stitched |
| Pixel size [μm x μm] | 20 x 20 |
| Integration Time [µs] | 2 |
| Timing Resolution [ns] | < 9 (optional) |
| Particle Rate [kHz/mm ²] | TBD |
| Readout Architecture | Asynchronous |
| Power [mW/cm ²] | < 20 |
| NIEL [1MeV neq/cm ²] | 10 ¹⁰ [1] |
| TID [Mrad] | < 10 [1] |
| Noise [electrons] | < 50 |
| Fake Hit Rate [hits/s] | < 10 ⁻⁵ /evt/pix [2] |
| Interface Requirements | TBD |

Preliminary EIC MAPS sensor requirements

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[1] From EIC white paper, [2] ITS2/ALPIDE specification

M. Mager | ITS3 kickoff | 04.12.2019

ITS3 detector concept & EIC vertex layers

- ITS3 uses design and post-processing techniques to reach an extremely low material budget of 0.05% X/X₀ per layer
- □ Low power wafer-scale sensors, thinned to 20-40 µm, bent around the beam pipe → air-cooling, support and services outside active area
- Very attractive for the EIC vertex layers, possible option under investigation





Advantages of ITS3-like vertex layers at EIC

- Pre-CD0 simulations assumed an 18 mm beam pipe (green line)
- With the increased beam pipe diameter, an ITS2-derived EIC SVT would see a significant degradation of vertex resolution (blue line)
- Vertex layers based on the ITS3 design with 10 µm pixel pitch and 0.05% X/X₀ (red line), allow to overcome performance degradation due to the larger beam pipe and reach the same (even improved) vertex resolution



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Path to an EIC detector based on 65 nm MAPS

- Despite the large overlap, the EIC and ITS3 detectors have some significant differences, most notably the size
 - ITS3 is a 0.12 m², three layers, vertex detector
 - The new YR baseline configurations of the EIC SVT have an area of approximately 12 m² and 15 m², for <u>hybrid</u> and <u>all-Si</u> respectively
- □ Cost and yield of stitched wafer-scale sensors not compatible with use in the EIC detector outside the vertex layers → a reticule-size sensor version needed for the EIC tracking layers and disks
- Tracking layers and disks also need a dedicated, possibly more conventional design of support structures (staves, disks)
 - Dedicated engineering solutions need to be developed



YR baseline detector configurations

- New baseline based on the ITS3 sensor, services and support design
- □ Two configurations are simulated within the YR effort
 - <u>Hybrid</u> with gas outer tracker and end-caps
 - □ TPC barrel and large area MPGDs for end cap tracking
 - MPGD barrel and large area MPGDs for end cap tracking
 - <u>All-Si</u> compact tracker



 $\begin{array}{l} 10 \ \mu m \ pixel \ pitch \\ 0.05\% \ X/X_0 \ vtx \ layers \\ 0.55\% \ X/X_0 \ tracking \ layers \\ 0.24\% \ X/X_0 \ disks \end{array}$



EIC Silicon Consortium

- A group of institutions interested in joining the ITS3 R&D effort as a path to an EIC detector is starting to join together to form the EIC Silicon Consortium
- This group currently consists of LBNL, Birmingham, RAL CMOS Sensor Design group, Wuhan, BNL instrumentation division, JLAB, Daresbury and Liverpool
 - many other groups expressing strong interest and expected to join soon
- Very early/informal phase of development
 - Institutes joined, expressing areas of interest/contribution
 - A mailing list is setup for communications

EIC Silicon Consortium: sensor design effort

- The first effort of the consortium concentrates on contributing to the silicon design and characterization by joining the ITS3 sensor R&D
 - Work already underway with CERN/ITS3 to access the technology and join the relevant work packages
- Some of these institutes have already joined the ITS3 R&D effort formally, and more institutes will be joining the ITS3 R&D effort formally in the next few months
- See <u>lain's talk</u> for ongoing and planned work within ITS3 to develop the EIC MAPS sensor



EIC Silicon Consortium: planned activities

- As the silicon design progresses and the outlines of the EIC specific sensor fork take shape, we will start organizing our own internal work packages to address the parts of the detector implementation needed for an EIC application
 - These will include mass testing, module design, stave design, disc design, EIC specific infrastructure, etc.

It is our intention to develop a full silicon detector implementation and to integrate the consortium into an EIC Silicon Detector collaboration

□ If you want to join, please contact Leo Greiner <u>lcgreiner@lbl.gov</u>



Conclusion

- An efficient design path to an EIC silicon vertex and tracking detector has been identified based on 65 nm MAPS
- An international silicon consortium is forming to develop an ITS3derived EIC MAPS sensor with associated services, support and readout infrastructure
- ITS3-derived baseline detector configurations for hybrid and all-Si SVT concepts prepared for the EIC YR tracking WG studies
- Work has started towards the MAPS sensor development in 65 nm for the EIC SVT

